

# RS-232 TRANSCEIVER WITH SPLIT SUPPLY PIN FOR LOGIC SIDE

Check for Samples: TRS3253E-EP

#### **FEATURES**

- V<sub>L</sub> Pin for Compatibility With Mixed-Voltage Systems Down to 1.8 V on Logic Side
- Enhanced ESD Protection on RIN Inputs and DOUT Outputs
  - ±8 kV IEC 61000-4-2 Air-Gap Discharge
  - ±8 kV IEC 61000-4-2 Contact Discharge
  - ±15 kV Human-Body Model
- Low 300-μA Supply Current
- · Specified 1000-kbps Data Rate
- Auto Powerdown Plus Feature

#### **APPLICATIONS**

- Hand-Held Equipment
- PDAs
- Cell Phones
- Battery-Powered Equipment
- Data Cables

# SUPPORTS DEFENSE, AEROSPACE, AND MEDICAL APPLICATIONS

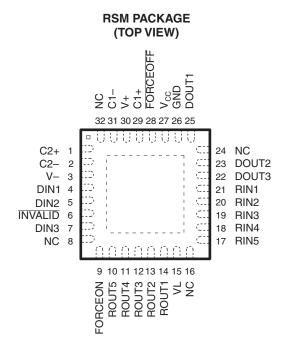
- Controlled Baseline
- One Assembly and Test Site
- One Fabrication Site
- Available in Military (-55°C to 125°C)
   Temperature Range
- Extended Product Life Cycle
- Extended Product-Change Notification
- Product Traceability

# **DESCRIPTION**

The TRS3253E is a three-driver and five-receiver RS-232 interface device, with split supply pins for mixed-signal operations. All RS-232 inputs and outputs are protected to  $\pm 8$  kV using the IEC 61000-4-2 Air-Gap Discharge method,  $\pm 8$  kV using the IEC 61000-4-2 Contact Discharge method, and  $\pm 15$  kV using the Human-Body Model.

The charge pump requires only four small  $0.1-\mu F$  capacitors for operation from a 3.3-V supply. The TRS3253E is capable of running at data rates up to 1000 kbps, while maintaining RS-232-compliant output levels.

The TRS3253E has a unique  $V_L$  pin that allows operation in mixed-logic voltage systems. Both driver in (DIN) and receiver out (ROUT) logic levels are pin programmable through the  $V_L$  pin. This eliminates the need for additional voltage level shifter while interfacing with low-voltage microcontroller or UARTs. The TRS3253E is available in a space-saving QFN package (4 mm  $\times$  4 mm RSM).



NC - No internal connection





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# **DESCRIPTION (CONTINUED)**

Auto-powerdown plus can be disabled when FORCEON and FORCEOFF are high. With auto-powerdown plus enabled, the device activates automatically when a valid signal is applied to any receiver or driver input. INVALID is high (valid data) if any receiver input voltage is greater than 2.7 V or less than –2.7 V, or has been between –0.3 V and 0.3 V for less than 30 µs. INVALID is low (invalid data) if all receiver input voltages are between –0.3 V and 0.3 V for more than 30 µs. Refer to Figure 6 for receiver input levels.

#### ORDERING INFORMATION(1)

$T_J$	PACKAGE	ORDERABLE PART NUMBER	TOP-SIDE MARKING	VID NUMBER
-55°C to 125°C	QFN - RSM	TRS3253EMRSMREP	RS53EP	V62/13621-01XE

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

#### **FUNCTION TABLES**

#### Each Driver(1)

	INPUTS		ОИТРИТ		
DIN	FORCEON	FORCEOFF	TIME ELAPSED SINCE LAST RIN OR DIN TRANSITION	DOUT	DRIVER STATUS
X	Χ	L	X	Z	Powered off
L	Н	Н	X	Н	Normal operation with
Н	Н	Н	X	L	auto-powerdown plus disabled
L	L	Н	<30 µs	Н	Normal operation with
Н	L	Н	<30 µs	L	auto-powerdown plus enabled
L	L	Н	>30 µs	Z	Powered off by
Н	L	Н	>30 µs	Z	auto-powerdown plus feature

<sup>(1)</sup> H = high level, L = low level, X = irrelevant, Z = high impedance

## Each Receiver<sup>(1)</sup>

	INPU	JTS	OUTPUTS	
RIN1-RIN5	FORCEOFF	TIME ELAPSED SINCE LAST RIN OR DIN TRANSITION ROUT1-ROUT5		RECEIVER STATUS
X	L	X	Z	Powered off
L	Н	<30 µs	Н	Normal operation with
Н	Н	<30 µs	L	auto-powerdown plus
Open	Н	<30 µs	Н	disabled/enabled

(1) H = high level, L = low level, X = irrelevant, Z = high impedance (off), Open = input disconnected or connected driver off

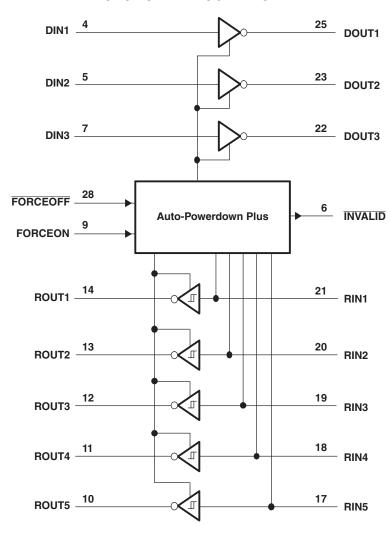
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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

## **FUNCTIONAL BLOCK DIAGRAM**





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## **TERMINAL FUNCTIONS**

TERMINAL		DESCRIPTION		
NAME	RSM	DESCRIPTION		
C1+, C2+	29, 1	Positive terminal of the voltage-doubler charge-pump capacitor		
V+	30	5.5-V supply generated by the charge pump		
C1-, C2-	31, 2	Negative terminal of the voltage-doubler charge-pump capacitor		
INVALID	6	Invalid Output Pin		
V-	3	-5.5-V supply generated by the charge pump		
DIN1 DIN2 DIN3	4 5 7	Driver inputs		
ROUT5 - ROUT1	10, 11, 12, 13, 14	Receiver outputs. Swing between 0 and V <sub>L</sub> .		
$V_L$	15	Logic-level supply. All CMOS inputs and outputs are referenced to this supply.		
RIN5-RIN1	17, 18, 19, 20, 21	RS-232 receiver inputs		
DOUT3 DOUT2 DOUT1	22 23 25	RS-232 driver outputs		
GND	26	Ground		
V <sub>CC</sub>	27	3-V to 5.5-V supply voltage		
FORCEOFF	28	Powerdown Control input (Refer to Truth Table)		
FORCEON	9	Powerdown Control input (Refer to Truth Table)		



### **ABSOLUTE MAXIMUM RATINGS(1)**

over junction temperature range (unless otherwise noted)

			MIN	MAX	UNIT
	V <sub>CC</sub> to GND		-0.3	6	V
	$V_L$ to GND		-0.3	$V_{CC} + 0.3$	V
	V+ to GND		-0.3	7	V
	V- to GND		0.3	-7	V
	V+ +  V-  <sup>(2)</sup>			13	V
V	lonut voltogo	DIN, FORCEOFF to GND, FORCEON to GND	-0.3	6	V
VI	input voitage	RIN to GND		±25	V
V	V+ to GND V- to GND V+ +  V- (2) Input voltage Output voltage Junction temperature	DOUT to GND		±13.2	V
Vo	Output voltage	ROUT	-0.3	$V_{L} + 0.3$	V
$T_J$	Junction temperature			150	°C
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

(2) V+ and V- can have maximum magnitudes of 7 V, but their absolute difference cannot exceed 13 V.

#### THERMAL INFORMATION

		TRS3253E-EP	
	THERMAL METRIC <sup>(1)</sup>	RSM	UNITS
$\theta_{JA}$	Junction-to-ambient thermal resistance (2)	37.2	
$\theta_{JCtop}$	Junction-to-case (top) thermal resistance <sup>(3)</sup>	30.1	
$\theta_{JB}$	Junction-to-board thermal resistance (4)	7.8	20044
ΨЈТ	Junction-to-top characterization parameter <sup>(5)</sup>	0.4	°C/W
ΨЈВ	Junction-to-board characterization parameter <sup>(6)</sup>	7.6	
$\theta_{JCbot}$	Junction-to-case (bottom) thermal resistance (7)	2.4	

- (1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter, ψ<sub>JT</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ<sub>JB</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).
- (7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.



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#### RECOMMENDED OPERATING CONDITIONS

				MIN	MAX	UNIT
$V_{CC}$	Supply voltage			3	5.5	V
$V_{L}$	Supply voltage			1.65	$V_{CC}$	V
	Input logic threshold low		V <sub>L</sub> = 3 V or 5.5 V		8.0	
		DIN, FORCEOFF, FORCEON	$V_{L} = 2.3 \text{ V}$		0.6	V
			V <sub>L</sub> = 1.65 V		0.5	
			$V_{L} = 5.5 \text{ V}$	2.4		
		DIN FORCEOUS	$V_L = 3 V$	2.0		V
	Input logic threshold high	DIN, FORCEOFF, FORCEON	V <sub>L</sub> = 2.7 V	1.4		V
			V <sub>L</sub> = 1.95 V	1.25		
	Junction temperature			-55	125	°C
	Receiver input voltage			-25	25	V

# ELECTRICAL CHARACTERISTICS(1)

over junction temperature range,  $V_{CC} = V_L = 3$  V to 5.5 V, C1–C4 = 0.1  $\mu F$  (tested at 3.3 V  $\pm$  10%), C1 = 0.047  $\mu F$ , C2–C4 =  $0.33 \mu F$  (tested at 5 V ± 10%) (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP <sup>(2)</sup>	MAX	UNIT
$I_{l}$	Input leakage current	FORCEOFF, FORCEON			±0.01	±2.9	μΑ
		Auto-powerdown plus disabled	No load, FORCEOFF and FORCEON at V <sub>CC</sub>		0.5	1.11	mA
loc	Supply current	Powered off	No load, FORCEOFF at GND		1	10	
Icc	$(T_J = 25^{\circ}C)$	Auto-powerdown plus enabled	No load, FORCEOFF at V <sub>CC</sub> , FORCEON at GND, All RIN are open or grounded		1	10	μΑ

<sup>(1)</sup> Testing supply conditions are C1–C4 = 0.1  $\mu$ F at  $V_{CC}$  = 3.3 V ± 0.15 V; C1–C4 = 0.22  $\mu$ F at  $V_{CC}$  = 3.3 V ± 0.3 V; and C1 = 0.047  $\mu$ F and C2–C4 = 0.33  $\mu$ F at V<sub>CC</sub> = 5 V ± 0.5 V. All typical values are at V<sub>CC</sub> = 3.3 V or V<sub>CC</sub> = 5 V, and T<sub>J</sub> = 25°C.

## **ESD PROTECTION**

PARAMETER	TEST CONDITIONS 1 an-Body Model :		UNIT
	Human-Body Model	±15	
RIN, DOUT	IEC 61000-4-2 Air-Gap Discharge	±8	kV
	IEC 61000-4-2 Contact Discharge	±8	



#### RECEIVER SECTION

#### **Electrical Characteristics**

over junction temperature range,  $V_{CC} = V_L = 3$  V to 5.5 V, C1–C4 = 0.1  $\mu$ F (tested at 3.3 V  $\pm$  10%), C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F (tested at 5 V  $\pm$  10%),  $T_A = T_{MIN}$  to  $T_{MAX}$  (unless otherwise noted)

	PARAMETER	TEST C	CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
I <sub>off</sub>	Output leakage current	ROUT, receivers disab	led		±0.05	±25	μΑ
$V_{OL}$	Output voltage low	I <sub>OUT</sub> = 1.6 mA				0.4	V
V <sub>OH</sub>	Output voltage high	$I_{OUT} = -1 \text{ mA}$		V <sub>L</sub> - 0.6	$V_{L} - 0.1$		V
\/	land three hald law	T 25°C	V <sub>L</sub> = 5 V	0.8	1.2		V
$V_{IT-}$	Input threshold low	$T_J = 25^{\circ}C$	$V_{L} = 3.3 \text{ V}$	0.6	1.5		
\/	lanut throohold high	T 25°C	V <sub>L</sub> = 5 V		1.8	2.4	V
V <sub>IT+</sub>	Input threshold high	$T_J = 25^{\circ}C$	$V_{L} = 3.3 \text{ V}$		1.5	2.4	V
V <sub>hys</sub>	Input hysteresis				0.5		V
	Input resistance	$T_J = 25^{\circ}C$		3	5	7	kΩ

<sup>(1)</sup> Typical values are at  $V_{CC} = V_L = 3.3 \text{ V}$ ,  $T_J = 25^{\circ}\text{C}$ 

# **Switching Characteristics**

over junction temperature range,  $V_{CC} = V_L = 3 \text{ V}$  to 5.5 V, C1–C4 = 0.1  $\mu\text{F}$  (tested at 3.3 V  $\pm$  10%), C1 = 0.047  $\mu\text{F}$ , C2–C4 = 0.33  $\mu\text{F}$  (tested at 5 V  $\pm$  10%),  $T_J = T_{MIN}$  to  $T_{MAX}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS		UNIT
t <sub>PHL</sub>	Descriver propagation delay	Descriper input to receiver output C 450 pC	0.15	
t <sub>PLH</sub>	Receiver propagation delay	Receiver input to receiver output, C <sub>L</sub> = 150 pF		μs
t <sub>PHL</sub> - t <sub>PLH</sub>	Receiver skew		50	ns
t <sub>en</sub>	Receiver output enable time	From FORCEOFF	200	ns
t <sub>dis</sub>	Receiver output disable time	From FORCEOFF	200	ns

(1) Typical values are at  $V_{CC} = V_L = 3.3 \text{ V}, T_J = 25^{\circ}\text{C}.$ 

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#### **DRIVER SECTION**

#### **Electrical Characteristics**

over junction temperature range,  $V_{CC} = V_L = 3$  V to 5.5 V, C1–C4 = 0.1  $\mu F$  (tested at 3.3 V  $\pm$  10%), C1 = 0.047  $\mu F$ , C2–C4 = 0.33  $\mu$ F (tested at 5 V  $\pm$  10%), T<sub>J</sub> = T<sub>MIN</sub> to T<sub>MAX</sub> (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
V <sub>OH</sub>	Output voltage swing	All driver outputs loaded with 3 k $\Omega$ to ground, V <sub>CC</sub> = 3.1V to 5.5V	±5	±5.4		V
r <sub>O</sub>	Output resistance	$V_{CC} = V + = V - = 0$ , Driver output = $\pm 2 V$	300	10M		Ω
Ios	Output short-circuit current	$V_{T\_OUT} = 0$			±60	mA
	Output leakage current	$V_{T\_OUT} = \pm 12 \text{ V}, \overline{\text{FORCEOFF}} = \text{GND},$ $V_{CC} = 3 \text{ V to } 3.6 \text{ V}$			. 25	
I <sub>OZ</sub>		$V_{T\_OUT} = \pm 12 \text{ V}, \overline{\text{FORCEOFF}} = \text{GND},$ $V_{CC} = 4.5 \text{ V} \text{ to } 5.5 \text{ V}$			±25	μΑ
	Driver input hysteresis				0.5	V
	Input leakage current	DIN, FORCEOFF, FORCEON		±0.01	±2.9	μΑ

<sup>(1)</sup> Typical values are at  $V_{CC} = V_L = 3.3 \text{ V}$ ,  $T_J = 25^{\circ}\text{C}$ 

# **Timing Requirements**

over junction temperature range,  $V_{CC} = V_L = 3$  V to 5.5 V, C1–C4 = 0.1  $\mu$ F (tested at 3.3 V  $\pm$  10%), C1 = 0.047  $\mu$ F, C2–C4 = 0.33  $\mu$ F (tested at 5 V  $\pm$  10%),  $T_j = T_{MIN}$  to  $T_{MAX}$  (unless otherwise noted)

	PARAMETER			MIN	TYP <sup>(1)</sup>	MAX	UNIT
	Maximum data rate	$R_L = 3 \text{ k}\Omega$ , $C_L = 200 \text{ pF}$ , One	1000			kbps	
	Time-to-exit powerdown	$ V_{T_{-}OUT}  > 3.7 \text{ V}$		100		μs	
t <sub>PHL</sub> - t <sub>PLH</sub>	Driver skew <sup>(2)</sup>			100		ns	
	Transition-region slew rate	$\begin{array}{l} V_{CC}=3.3 \text{ V}, \\ T_j=25^{\circ}\text{C}, \\ R_L=3 \text{ k}\Omega \text{ to 7 k}\Omega, \\ \text{Measured from 3 V} \\ \text{to } -3 \text{ V or } -3 \text{ V to 3 V} \end{array}$	C <sub>L</sub> = 150 pF to 1000 pF	15		150	V/µs

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Typical values are at  $V_{CC}$  =  $V_L$  = 3.3 V,  $T_J$  = 25°C. Driver skew is measured at the driver zero crosspoint.



#### **AUTO-POWERDOWN SECTION**

#### **Electrical Characteristics**

over recommended ranges of supply voltage and junction temperature (unless otherwise noted) (see Figure 7)

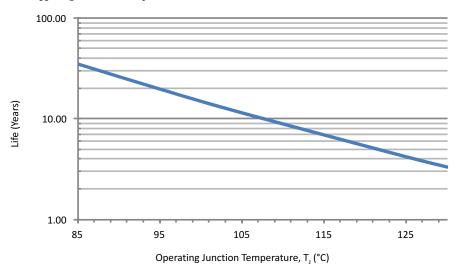
	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
V <sub>IT+(valid)</sub>	Receiver input threshold for INVALID high-level output voltage	FORCEON = GND, FORCEOFF = V <sub>L</sub>		2.7	٧
V <sub>IT-(valid)</sub>	Receiver input threshold for INVALID high-level output voltage	FORCEON = GND, FORCEOFF = V <sub>L</sub>	-2.7		V
V <sub>T(invalid)</sub>	Receiver input threshold for INVALID low-level output voltage	FORCEON = GND, FORCEOFF = V <sub>L</sub>	-0.3	0.3	٧
V <sub>OH</sub>	INVALID high-level output voltage	I <sub>OH</sub> = -1 mA, FORCEON = GND, FORCEOFF = V <sub>L</sub>	V <sub>L</sub> – 0.6		٧
V <sub>OL</sub>	INVALID low-level output voltage	$I_{OL}$ = 1.6 mA, FORCEON = GND, FORCEOFF = $V_L$		0.4	V

# **Switching Characteristics**

over recommended ranges of supply voltage and junction temperature (unless otherwise noted) (see Figure 7)

	PARAMETER	MIN	TYP <sup>(1)</sup>	MAX	UNIT
t <sub>valid</sub>	Propagation delay time, low- to high-level output		0.1		μs
t <sub>invalid</sub>	Propagation delay time, high- to low-level output		50		μs
t <sub>en</sub>	Supply enable time		25		μs
t <sub>dis</sub>	Receiver or driver edge to auto-powerdown plus		30		μs

(1) All typical values are at  $V_{CC} = V_L = 3.3 \text{ V}$  and  $T_J = 25^{\circ}\text{C}$ .



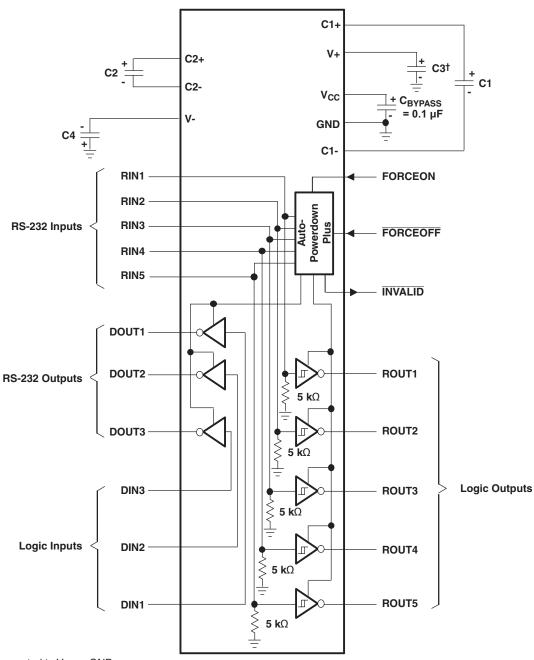
- (1) See datasheet for absolute maximum and minimum recommended operating conditions.
- (2) Silicon operating life design goal is 10 years at 105°C junction temperature (does not include package interconnect life).
- (3) Enhanced plastic product disclaimer applies.

Figure 1. TRS3253E-EP Operating Life Derating Chart

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#### **APPLICATION INFORMATION**



 $<sup>^{\</sup>dagger}$  C3 can be connected to  $V_{CC}$  or GND.

NOTES: A. Resistor values shown are nominal.

B. Nonpolarized ceramic capacitors are acceptable. If polarized tantalum or electrolytic capacitors are used, they should be connected as shown.

#### V<sub>CC</sub> vs CAPACITOR VALUES

V <sub>CC</sub>	C1	C2, C3, and C4
$\begin{array}{c} \textbf{3.3 V} \pm \textbf{0.3 V} \\ \textbf{5 V} \pm \textbf{0.5 V} \\ \textbf{3 V to 5.5 V} \end{array}$	0.1 μF 0.047 μF 0.1 μF	0.1 μF 0.33 μF 0.47 μF

Figure 2. Typical Operating Circuit and Capacitor Values

Product Folder Links: TRS3253E-EP

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#### PARAMETER MEASUREMENT INFORMATION

- A. C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 250 kbit/s,  $Z_O = 50 \Omega$ , 50% duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

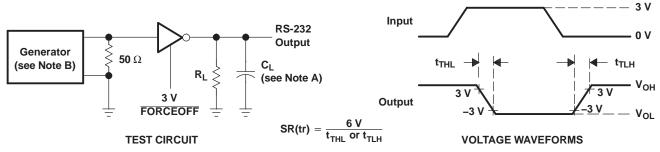


Figure 3. Driver Slew Rate

- A. C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 250 kbit/s,  $Z_O = 50 \Omega$ , 50% duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.

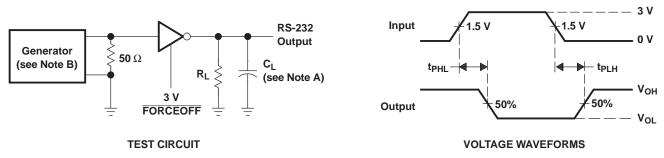


Figure 4. Driver Pulse Skew

- A. C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics:  $Z_0 = 50 \Omega$ , 50% duty cycle,  $t_r \le 10$  ns.  $t_f \le 10$  ns.

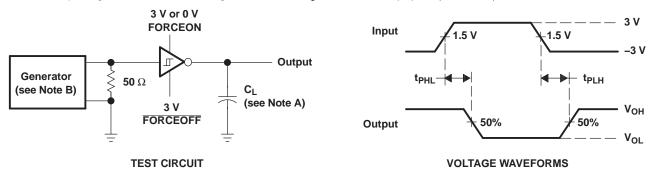


Figure 5. Receiver Propagation Delay Times

- A. C<sub>L</sub> includes probe and jig capacitance.
- B. The pulse generator has the following characteristics:  $Z_0$  = 50  $\Omega$ , 50% duty cycle,  $t_r \le 10$  ns,  $t_f \le 10$  ns.
- C.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- D.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .



# PARAMETER MEASUREMENT INFORMATION (continued)

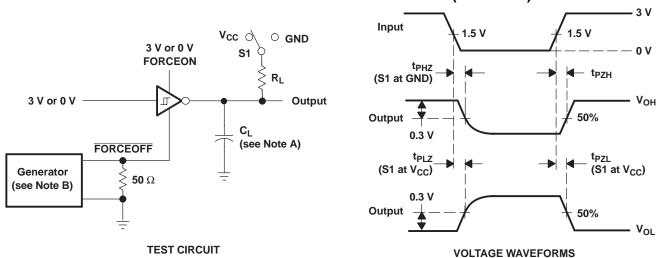
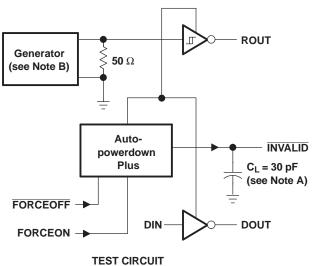


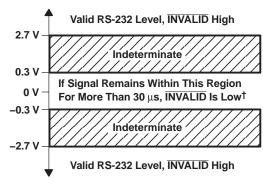
Figure 6. Receiver Enable and Disable Times

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# PARAMETER MEASUREMENT INFORMATION (continued)





<sup>†</sup> Auto-powerdown plus disables drivers and reduces supply current to 1 μA.

- NOTES: A.  $C_L$  includes probe and jig capacitance.
  - B. The pulse generator has the following characteristics: PRR = 5 kbit/s,  $Z_O$  = 50  $\Omega$ , 50% duty cycle,  $t_f \le 10$  ns,  $t_f \le 10$  ns.

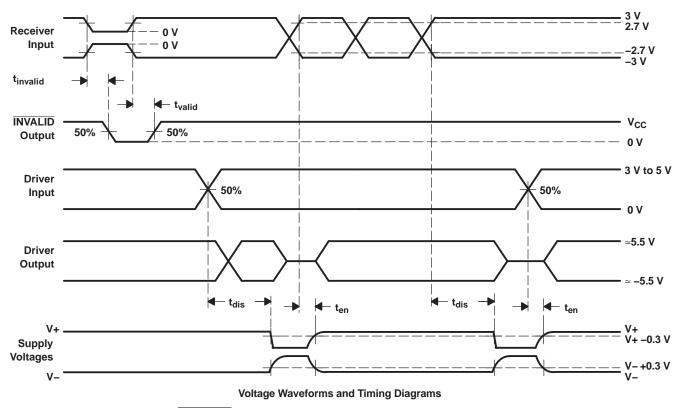


Figure 7. INVALID Propagation-Delay Times and Supply-Enabling Time



# PACKAGE OPTION ADDENDUM

10-Dec-2020

#### PACKAGING INFORMATION

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Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TRS3253EMRSMREP	ACTIVE	VQFN	RSM	32	3000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-55 to 125	RS53EP	Samples
V62/13621-01XE	ACTIVE	VQFN	RSM	32	3000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-55 to 125	RS53EP	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

10-Dec-2020

#### OTHER QUALIFIED VERSIONS OF TRS3253E-EP:

www.ti.com

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

PACKAGE MATERIALS INFORMATION

www.ti.com 18-Nov-2020

# TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TRS3253EMRSMREP	VQFN	RSM	32	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2

# **PACKAGE MATERIALS INFORMATION**

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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
TRS3253EMRSMREP	VQFN	RSM	32	3000	853.0	449.0	35.0	

4 x 4, 0.4 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

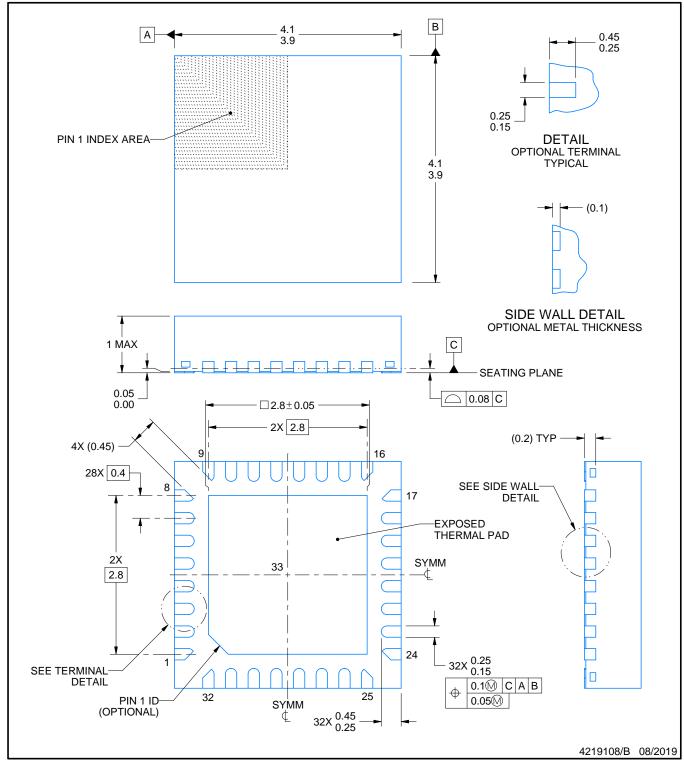
This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.







PLASTIC QUAD FLATPACK - NO LEAD



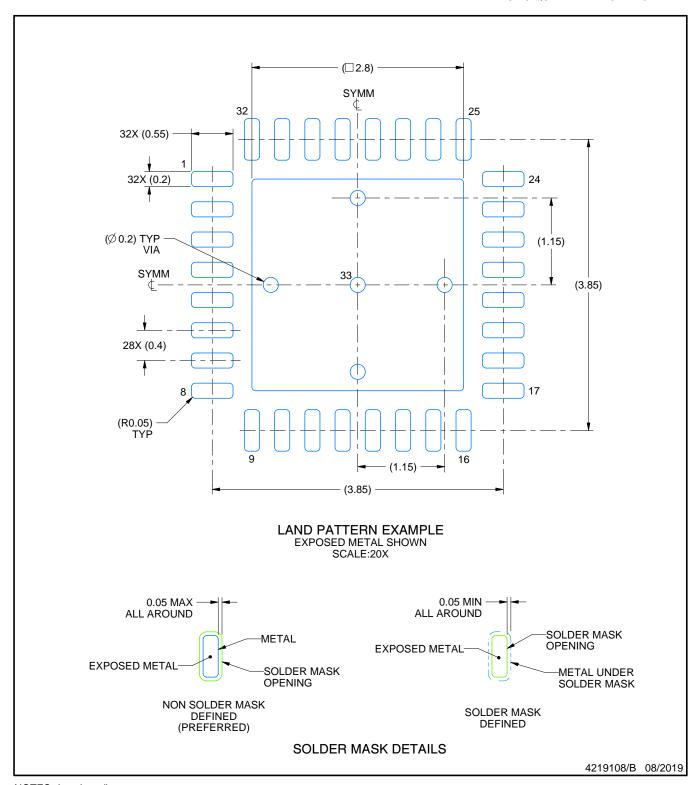
#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

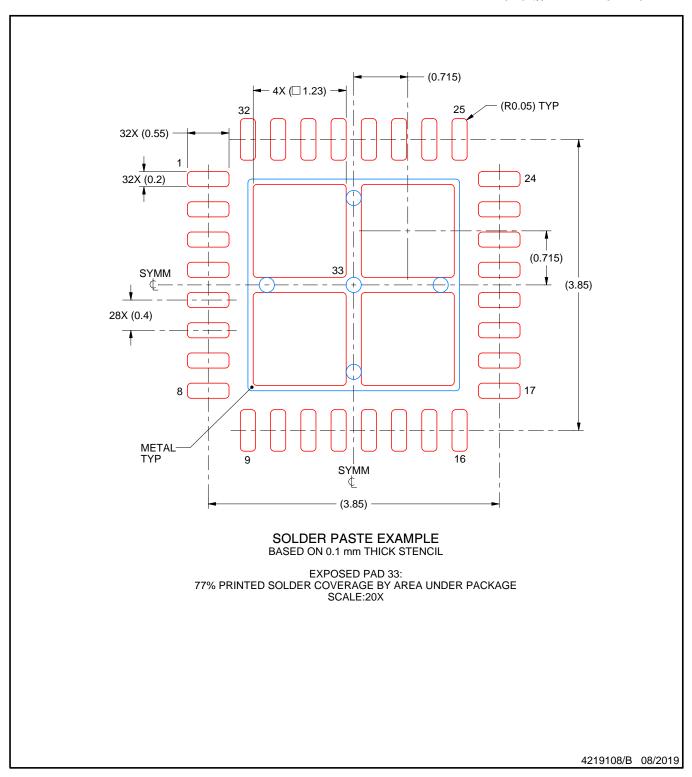


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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